10/709,729

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	11200	(integrated adj circuit$1 or ic$1 or die$1 or dice$1) and test$4 and (retest$4 or re-test$4 or re adj test$4 or (first adj test$4 and second adj test$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 11:20
L2	7736	1 and group$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 11:19
L3	257	(retest$4 or re-test$4 or re adj test$4 or (first adj test$4 and second adj test$4)) near (defect$4 or fault$4 or fail$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 11:21
L4	64	2 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 11:22